



钜地半导体
Tudi Semiconductor

Product Specification

TUDI-SN65HVD3082E/ SN65HVD3085E/ SN65HVD3088E

Low power RS-485 transceiver

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**semiconductor device
manufacturer**

- Design
- research and development
- production
- and sales



Features

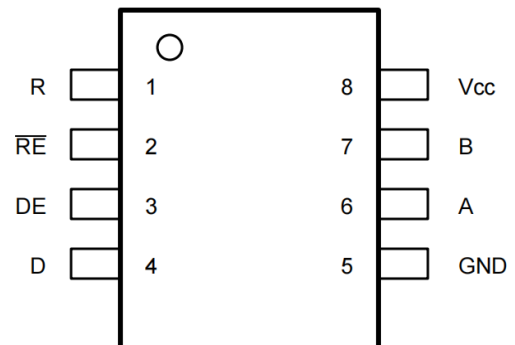
- Complies with or exceeds TIA/EIA-485A standard requirements
- Low static power
 - 0.3mA active mode
 - 1nA in shutdown mode
- 1/8 unit load, up to 256 nodes on a single bus
- Up to 1kV bus pin ESD protection
- Industry-standard SN75176 package
- Fail-safe receiver (bus open, bus short, bus idle)
- Interference- power-up and power-down bus inputs and outputs

Applications

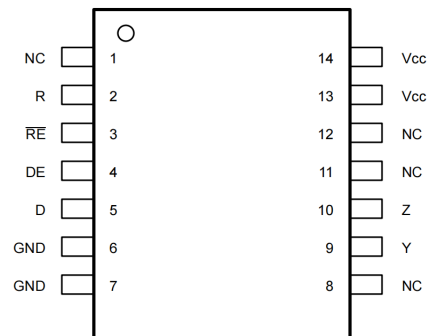
- Energy metering networks
- Motor control
- Power inverters
- Industrial automation
- Building automation networks
- Battery-powered applications
- Tele equipment

Description

The SNx5HVD308xE is a half-duplex transceiver designed specifically for RS-485 data bus networks. These are powered by a 5V supply and are fully compliant with the TIA/EIA-485A standard. By controlling the conversion time, these devices are suitable for transmitting over long twisted-pair cables. The SN65HVD3082E and SN75HVD3082E are optimized to support signal transmission rates up to 100kbps. The SN65HVD3085E is suitable for data transmission up to 1Mbps, while the SN65HVD3088 is suitable for applications requiring signal transmission rates up to 20Mbps.



SOIC PDIP and VSSOP Packages, 8-Pin
(Top View)

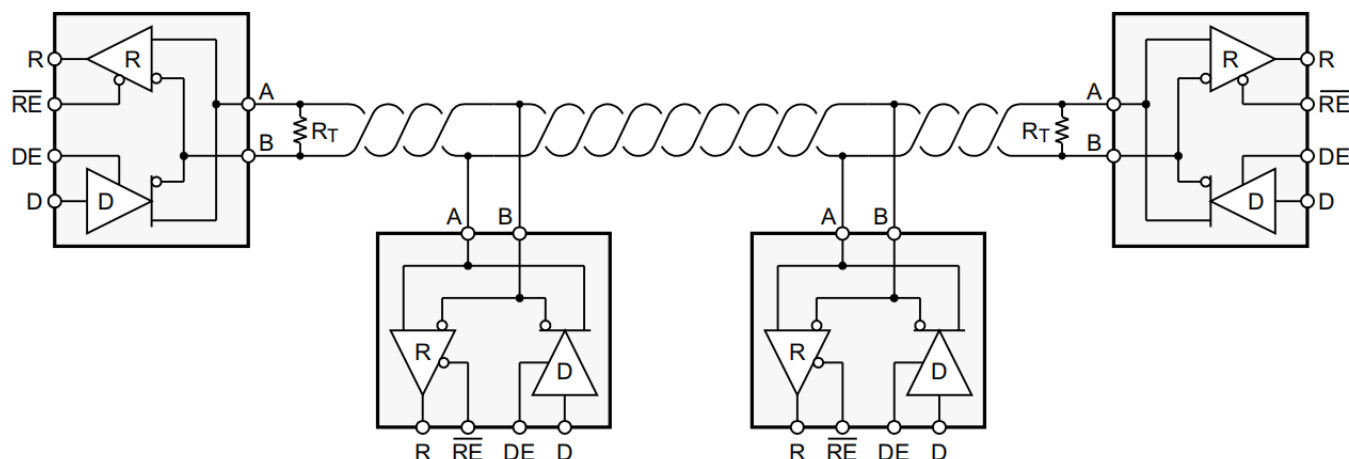


SN65HVD3088E, NS Package, 14-pin
(Top View)



These devices are designed to operate at very low supply currents (typically 0.3mA, excluding load). In the non-operating shutdown, the supply current can be reduced to a few nanoamps, making these devices an ideal choice for power-sensitive applications.

These devices feature a wide common-mode range and ESD protection levels, making them suitable for demanding applications such as smart meter networks, electrical inverters, status and command signals on telecom racks, wired chassis interconnects, and industrial automation where noise immunity is critical. These devices comply with the industry-standard dimensions of SN75176 devices. The power-on reset circuit keeps the outputs in a high impedance state until the supply voltage stabilizes. The thermal shutdown function protects the devices from damage caused by system failures. SN75HVD3082E features an temperature range of 0°C to 70°C, while SN65HVD30xE features an operating temperature range of – 40°C to 5°C. The D package version of SN65HVD3082E features an operating temperature range of – 40°C to 105°.



简化原理图

表 5-1. Pin Functions

PIN		TYPE	DESCRIPTION
NAME	NO.		
R	1	Digital output	Receive data output
$\overline{RE}$	2	Digital input	Receiver enable, active low
DE	3	Digital input	Driver enable, active high
D	4	Digital input	Driver data input
GND	5	Reference potential	Local device ground
A	6	Bus input/output	Driver output or receiver input (complementary to B)
B	7	Bus input/output	Driver output or receiver input (complementary to A)
V_{CC}	8	Supply	4.5-V to 5.5-V supply



表 5-2. Pin Functions, NS Package

PIN		TYPE	DESCRIPTION
NAME	NO.		
NC	1, 8	No Connect	Not Electrically Connected
R	2	Digital output	Receive data output
RE	3	Digital input	Receiver enable, active low
DE	4	Digital input	Driver enable, active high
D	5	Digital input	Driver data input
GND	6, 7	Reference potential	Local device ground
Y	9	Bus I/O	Differential transceiver input and output (complementary to Z)
Z	10	Bus I/O	Differential transceiver input and output (complementary to Y)
NC	12	No Connect	Not Electrically Connected
NC	11	No Connect	Not Electrically Connected
V _{CC}	13,14	Supply	4.5-V to 5.5-V supply

6 Specifications

6.1 Absolute Maximum Ratings

over operating free-air temperature range unless otherwise noted^{(1) (2)}

	MIN	MAX	UNIT
Supply voltage, V _{CC}	-0.5	7	V
Voltage at A or B	-9	14	V
Voltage at any logic pin	-0.3	V _{CC} + 0.3	V
Receiver output current	-24	24	mA
Voltage input, transient pulse, A and B, through 100 Ω (see 图 7-13)	-50	50	V
Junction Temperature, T _J		170	°C
Storage temperature, T _{stg}	-65	150	°C

- (1) Operation outside the *Absolute Maximum Ratings* may cause permanent device damage. *Absolute Maximum Ratings* do not imply functional operation of the device at these or any other conditions beyond those listed under *Recommended Operating Conditions*. If used outside the *Recommended Operating Conditions* but within the *Absolute Maximum Ratings*, the device may not be fully functional, and this may affect device reliability, functionality, performance, and shorten the device lifetime
- (2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

6.2 ESD Ratings

			VALUE	UNIT
V _(ESD) Electrostatic discharge	Human body model (HBM), per ANSI/ESDA/JEDEC JS-001 ⁽¹⁾	Bus pins and GND	±15000	V
		All pins	±4000	
	Charged-device model (CDM), per JEDEC specification JESD22-C101 ⁽²⁾		±1000	
	Electrical Fast Transient/Burst, A, B, and GND ⁽³⁾		±4000	

- (1) JEDEC document JEP155 states that 500-V HBM allows safe manufacturing with a standard ESD control process.
- (2) JEDEC document JEP157 states that 250-V CDM allows safe manufacturing with a standard ESD control process.
- (3) Tested in accordance with IEC 61000-4-4.



6.3 Recommended Operating Conditions

over operating free-air temperature range unless otherwise noted⁽¹⁾

		MIN	NOM	MAX	UNIT
Supply voltage, V_{CC}		4.5		5.5	V
Voltage at any bus terminal (separately or common mode), V_I		-7		12	V
High-level input voltage (D, DE, or $\overline{RE}$ inputs), V_{IH}		2		V_{CC}	V
Low-level input voltage (D, DE, or $\overline{RE}$ inputs), V_{IL}		0		0.8	V
Differential input voltage, V_{ID}		-12		12	V
Output current, I_O	Driver	-60		60	mA
	Receiver	-8		8	
Differential load resistance, R_L		54	60		Ω
Signaling rate, $1/t_{UI}$	SN65HVD3082E, SN75HVD3082E			0.2	Mbps
	SN65HVD3085E			1	
	SN65HVD3088E			20	
Operating free-air temperature, T_A	SN65HVD3082E (D package)	-40		105	$^{\circ}\text{C}$
	SN65HVD3082E (DGK and P packages), SN65HVD3085E, SN65HVD3088E	-40		85	
	SN75HVD3082E	0		70	
Junction temperature, T_J		-40		130	$^{\circ}\text{C}$

(1) The algebraic convention, in which the least positive (most negative) limit is designated as minimum is used in this data sheet.

6.4 Thermal Information, SN65HVD308xE

THERMAL METRIC ⁽¹⁾		SN65HVD3085E, SN65HVD3088E		SN65HVD3088E	SN65HVD3088E	UNIT
		D (SOIC)	DGK (VSSOP)	P (PDIP)	NS (SO)	
		8 PINS	8 PINS	8 PINS	14 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	116.7	137.8	84.3	88.6	$^{\circ}\text{C}/\text{W}$
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	56.3	31.2	65.4	46.13	$^{\circ}\text{C}/\text{W}$
$R_{\theta JB}$	Junction-to-board thermal resistance	63.4	71.7	62.1	49.12	$^{\circ}\text{C}/\text{W}$
Ψ_{JT}	Junction-to-top characterization parameter	8.8	0.6	31.3	14.17	$^{\circ}\text{C}/\text{W}$
Ψ_{JB}	Junction-to-board characterization parameter	62.6	70.5	60.4	48.6	$^{\circ}\text{C}/\text{W}$

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.

6.5 Thermal Information, SNx5HVD3082E

THERMAL METRIC ⁽¹⁾		SN65HVD3082E, SN75HVD3082E		SN65HVD3082E	UNIT
		D (SOIC)	DGK (VSSOP)	P (PDIP)	
		8 PINS	8 PINS	8 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	114.4	142.2	88.1	$^{\circ}\text{C}/\text{W}$
$R_{\theta JC(top)}$	Junction-to-case (top) thermal resistance	55.1	35.8	65.9	$^{\circ}\text{C}/\text{W}$
$R_{\theta JB}$	Junction-to-board thermal resistance	61.6	75.6	69.0	$^{\circ}\text{C}/\text{W}$
Ψ_{JT}	Junction-to-top characterization parameter	8.8	0.8	35.2	$^{\circ}\text{C}/\text{W}$
Ψ_{JB}	Junction-to-board characterization parameter	60.8	74.8	64.3	$^{\circ}\text{C}/\text{W}$

(1) For more information about traditional and new thermal metrics, see the [Semiconductor and IC Package Thermal Metrics](#) application report.



6.6 Electrical Characteristics: Driver

over operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{OD} Differential output voltage	I _O = 0, No Load	3	4.3		V
	R _L = 54 Ω (see 图 7-1)	1.5	2.3		
	R _L = 100 Ω	2			
	V _{TEST} = -7 V to 12 V (see 图 7-2)	1.5			
Δ V _{OD} Change in magnitude of differential output voltage	See 图 7-1 and 图 7-2	-0.2	0	0.2	V
V _{OC(SS)} Steady-state common-mode output voltage	See 图 7-3	1	2.6	3	V
ΔV _{OC(SS)} Change in steady-state common-mode output voltage		-0.1	0	0.1	
V _{OC(PP)} Peak-to-peak common-mode output voltage	See 图 7-3		500		mV
I _{OZ} High-impedance output current	See receiver input currents in Electrical Characteristics: Receiver				
I _I Input current	D, DE	-100		100	μA
I _{OS} Short-circuit output current	-7 V ≤ V _O ≤ 12 V (see 图 7-7)	-250		250	mA

(1) All typical values are at 25°C and with a 5-V supply.

6.7 Electrical Characteristics: Receiver

over operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
V _{IT+} Positive-going differential input threshold voltage	I _O = -8 mA		-85	-10	mV
V _{IT-} Negative-going differential input threshold voltage	I _O = 8 mA	-200	-115		mV
V _{hys} Hysteresis voltage (V _{IT+} - V _{IT-})			30		mV
V _{OH} High-level output voltage	V _{ID} = 200 mV, I _{OH} = -8 mA (see 图 7-8)	4	4.6		V
V _{OL} Low-level output voltage	V _{ID} = -200 mV, I _O = 8 mA (see 图 7-8)		0.15	0.4	V
I _{OZ} High-impedance-state output current	V _O = 0 or V _{CC} , RE = V _{CC}	-1		1	μA
I _I Bus input current	V _{IH} = 12 V, V _{CC} = 5 V		0.04	0.1	mA
	V _{IH} = 12 V, V _{CC} = 0 V		0.06	0.125	
	V _{IH} = -7 V, V _{CC} = 5 V	-0.1	-0.04		
	V _{IH} = -7 V, V _{CC} = 0 V	-0.05	-0.03		
I _{IH} High-level input current, (RE)	V _{IH} = 2 V	-60	-30		μA
I _{IL} Low-level input current, (RE)	V _{IL} = 0.8 V	-60	-30		μA
C _{diff} Differential input capacitance	V _I = 0.4 sin (4E6πt) + 0.5 V, DE at 0 V		7		pF

(1) All typical values are at 25°C and with a 5-V supply.



6.8 Electrical Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS	MIN	TYP ⁽¹⁾	MAX	UNIT
I_{CC}	Driver and receiver enabled	D at V_{CC} or open, DE at V_{CC} , $\overline{RE}$ at 0 V, No load		425	900	μA
	Driver enabled, receiver disabled	D at V_{CC} or open, DE at V_{CC} , $\overline{RE}$ at V_{CC} , No load		330	600	μA
	Receiver enabled, driver disabled	D at V_{CC} or open, DE at 0 V, $\overline{RE}$ at 0 V, No load		300	600	μA
	Driver and receiver disabled	D at V_{CC} or open, DE at 0 V, $\overline{RE}$ at V_{CC}		0.001	2	μA
$P_{(AVG)}$	Average power dissipation	Input to D is a 50% duty cycle square wave at max specified signal rate $R_L = 54 \Omega$, $V_{CC} = 5.5 V$, $T_J = 130^\circ C$	ALL HVD3082E		203	mW
			ALL HVD3085E		205	
			ALL HVD3088E		276	

(1) All typical values are at $25^\circ C$ and with a 5-V supply.

6.9 Switching Characteristics: Driver

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
t_{PLH} t_{PHL}	Propagation delay time, low-to-high-level output Propagation delay time, high-to-low-level output	$R_L = 54 \Omega$, $C_L = 50 pF$ (see 图 7-4)	HVD3082E		700	1300	ns
			HVD3085E		150	500	
			HVD3088E		12	20	
t_r t_f	Differential output signal rise time Differential output signal fall time	$R_L = 54 \Omega$, $C_L = 50 pF$ (see 图 7-4)	HVD3082E	500	900	1500	ns
			HVD3085E		200	300	
			HVD3088E		7	15	
$t_{sk(p)}$	Pulse skew ($ t_{PHL} - t_{PLH} $)	$R_L = 54 \Omega$, $C_L = 50 pF$ (see 图 7-4)	HVD3082E		20	200	ns
			HVD3085E		5	50	
			HVD3088E		1.4	2	
t_{PZH} t_{PZL}	Propagation delay time, high-impedance-to-high-level output Propagation delay time, high-impedance-to-low-level output	$R_L = 110 \Omega$, $\overline{RE}$ at 0 V (see 图 7-5 and 图 7-6)	HVD3082E		2500	7000	ns
			HVD3085E		1000	2500	
			HVD3088E		13	30	
t_{PHZ} t_{PLZ}	Propagation delay time, high-level-to-high-impedance output Propagation delay time, low-level-to-high-impedance output	$R_L = 110 \Omega$, $\overline{RE}$ at 0 V (see 图 7-5 and 图 7-6)	HVD3082E		80	200	ns
			HVD3085E		60	100	
			HVD3088E		12	30	
$t_{PZH(SHDN)}$ $t_{PZL(SHDN)}$	Propagation delay time, shutdown-to-high-level output Propagation delay time, shutdown-to-low-level output	$R_L = 110 \Omega$, $\overline{RE}$ at V_{CC} (see 图 7-5)	HVD3082E		3500	7000	ns
			HVD3085E		2500	4500	
			HVD3088E		1600	2600	



6.10 Switching Characteristics

over operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		MIN	TYP	MAX	UNIT
t_{PLH}	Propagation delay time, low-to-high-level output	$C_L = 15 \text{ pF}$ (see 图 7-9)	HVD3082E HVD3085E		75	200	ns
			HVD3086E			100	
t_{PHL}	Propagation delay time, high-to-low-level output		HVD3082E HVD3085E		79	200	ns
			HVD3088E			100	
$t_{sk(p)}$	Pulse skew ($ t_{PHL} - t_{PLH} $)		HVD3082E HVD3085E		4	30	ns
			HVD3088E			10	
t_r	Output signal rise time	$V_{ID} = -1.5 \text{ V to } 1.5 \text{ V}$, $C_L = 15 \text{ pF}$ (see 图 7-9)			1.5	3	ns
t_f	Output signal fall time				1.8	3	
t_{PZH}	Output enable time to high level	$C_L = 15 \text{ pF}$, DE at 3 V (see 图 7-10 and 图 7-11)	HVD3082E HVD3085E		5	50	ns
			HVD3088E			30	
t_{PZL}	Output enable time to low level		HVD3082E HVD3085E		10	50	ns
			HVD3088E			30	
t_{PHZ}	Output enable time from high level		HVD3082E HVD3085E		5	50	ns
			HVD3088E			30	
t_{PLZ}	Output disable time from low level		HVD3082E HVD3085E		8	50	ns
			HVD3088E			30	
$t_{PZH(SHDN)}$	Propagation delay time, shutdown-to-high-level output	$C_L = 15 \text{ pF}$, DE at 0 V, (see 图 7-12)			1600	3500	ns
$t_{PZL(SHDN)}$	Propagation delay time, shutdown-to-low-level output				1700	3500	



7 Parameter Measurement Information

Test load capacitance includes probe and jig capacitance (unless otherwise specified). Signal generator characteristics: rise and fall time < 6 ns, pulse rate 100 kHz, 50% duty cycle. $Z_O = 50 \Omega$ (unless otherwise specified).

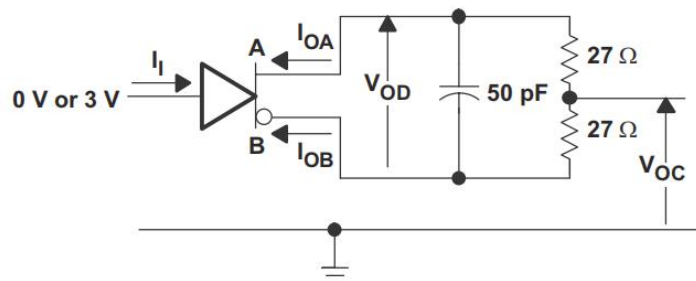


图 7-1. Driver Test Circuit, V_{OD} and V_{OC} Without Common-Mode Loading

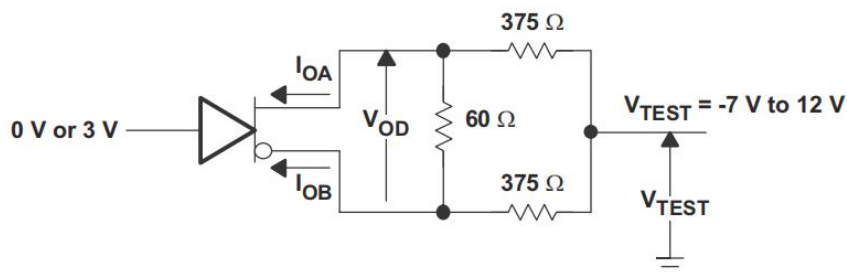


图 7-2. Driver Test Circuit, V_{OD} With Common-Mode Loading

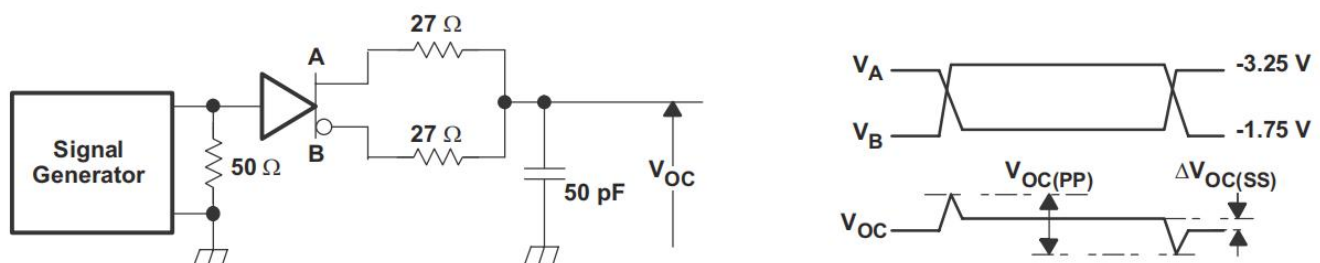


图 7-3. Driver V_{OC} Test Circuit and Waveforms

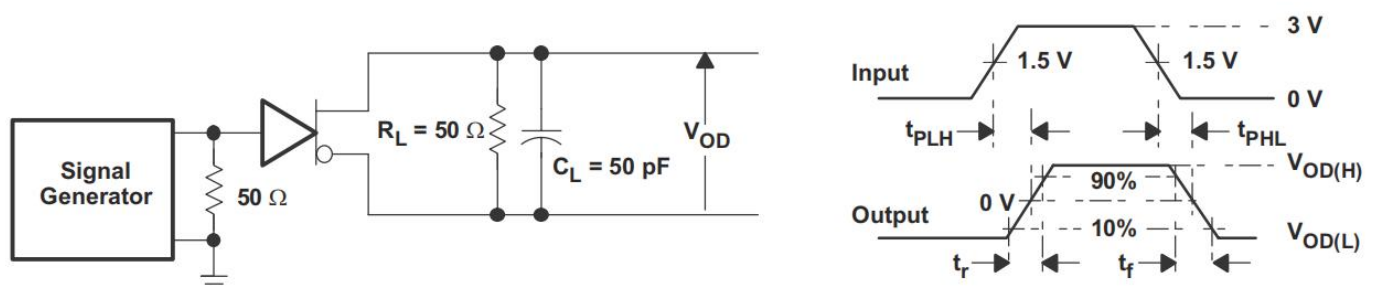


图 7-4. Driver Switching Test Circuit and Waveforms

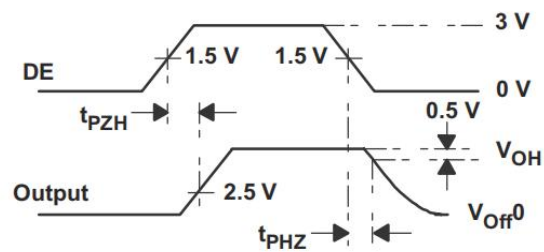
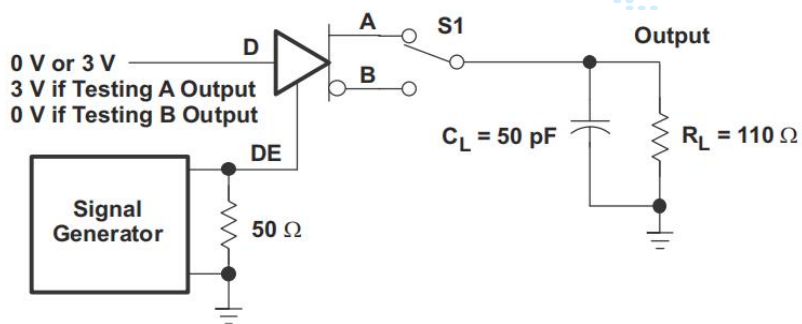


图 7-5. Driver Enable and Disable Test Circuit and Waveforms, High Output

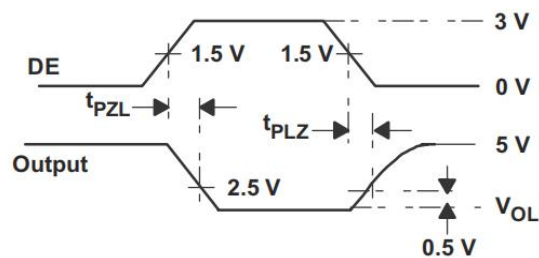
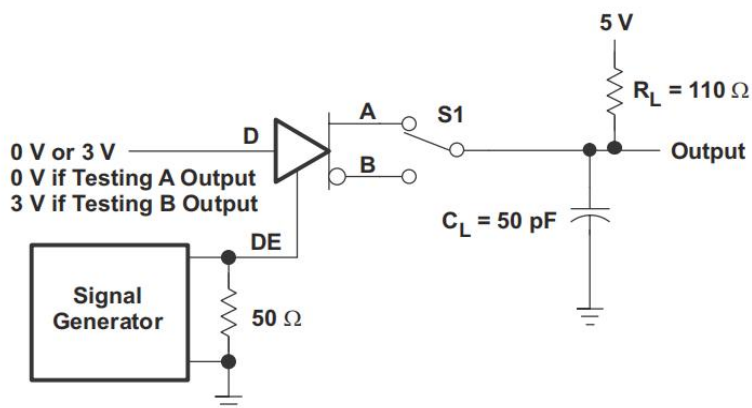


图 7-6. Driver Enable and Disable Test Circuit and Waveforms, Low Output

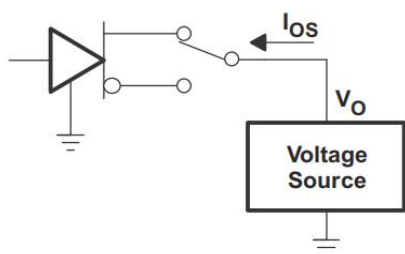


图 7-7. Driver Short-Circuit

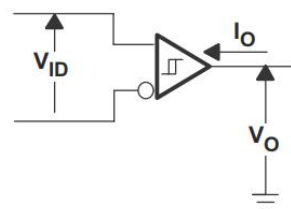


图 7-8. Receiver Switching Test Circuit and Waveforms

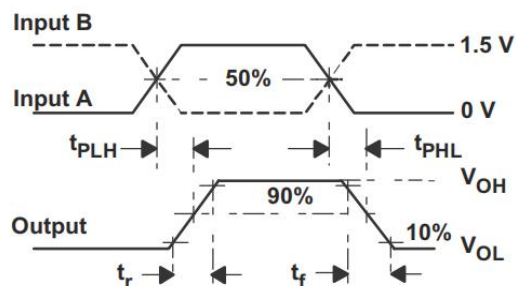
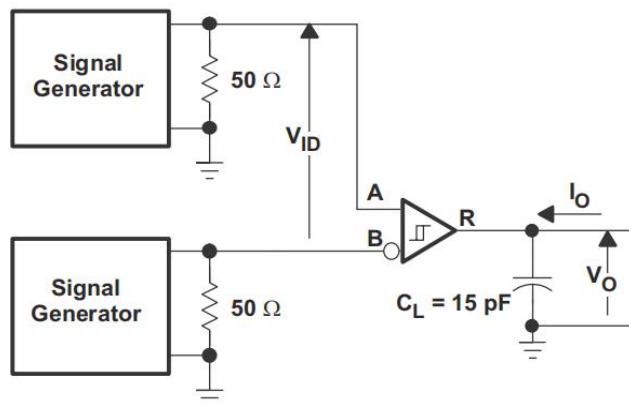


图 7-9. Receiver Switching Test Circuit and Waveforms

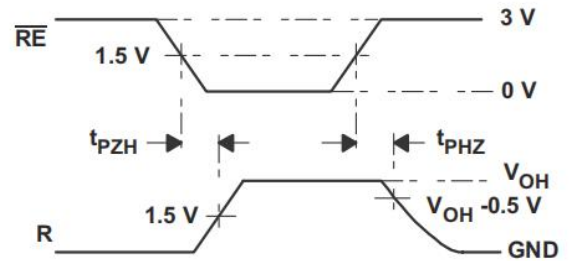
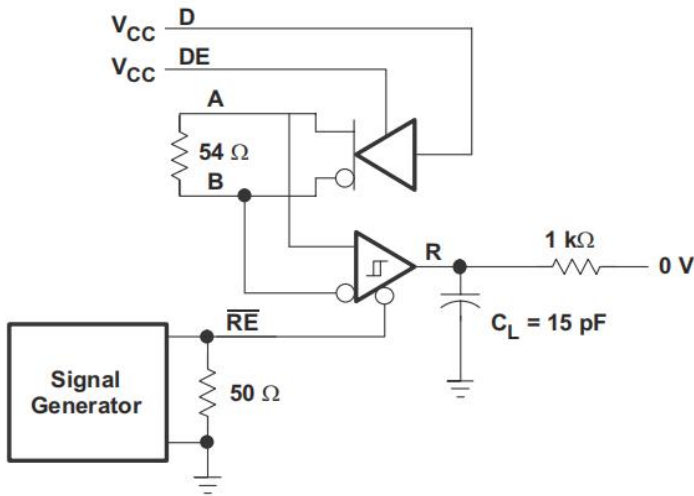


图 7-10. Receiver Enable and Disable Test Circuit and Waveforms, Data Output High

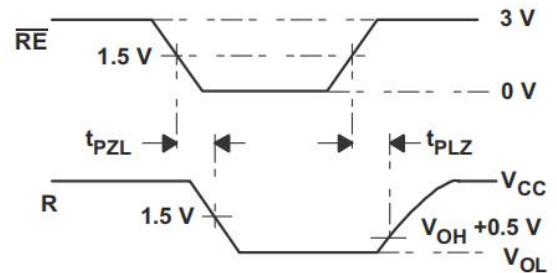
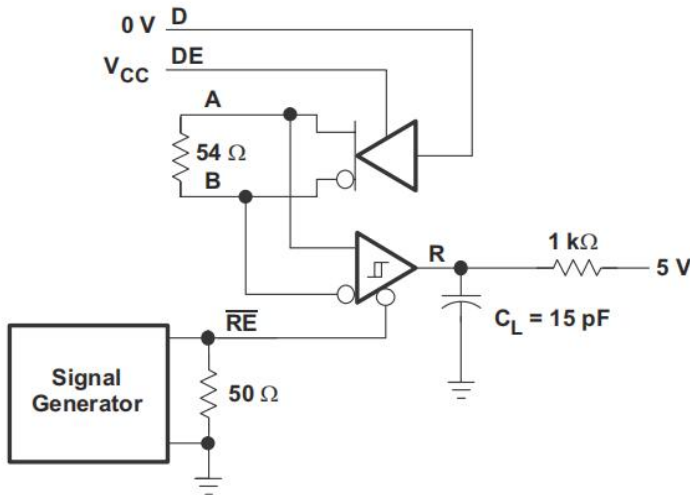


图 7-11. Receiver Enable and Disable Test Circuit and Waveforms, Data Output Low

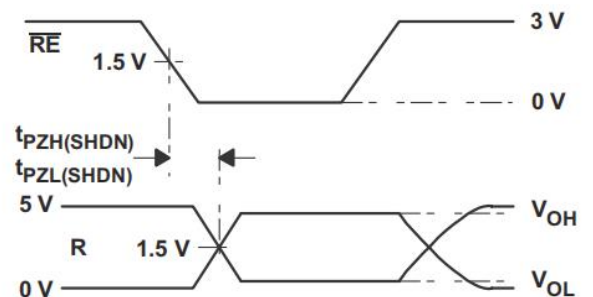
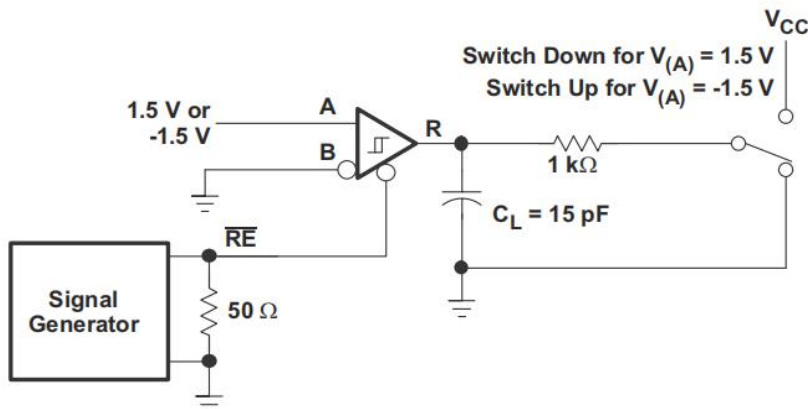


图 7-12. Receiver Enable From Shutdown Test Circuit and Waveforms

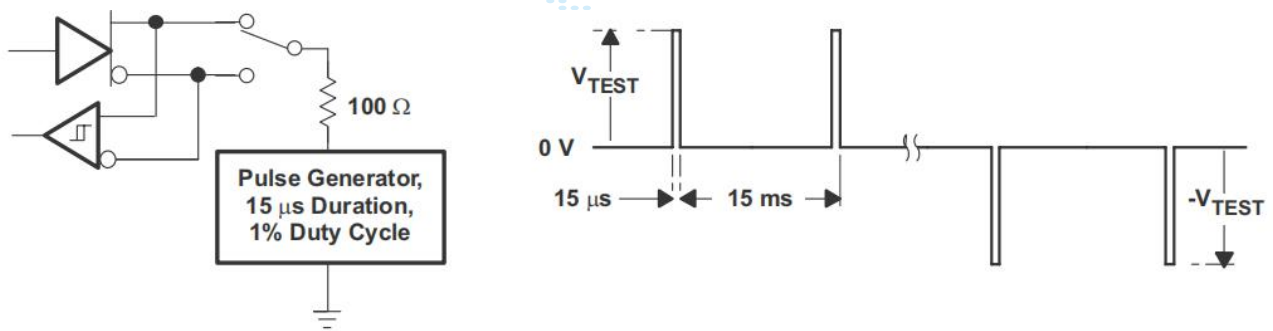


图 7-13. Test Circuit and Waveforms, Transient Overvoltage Test

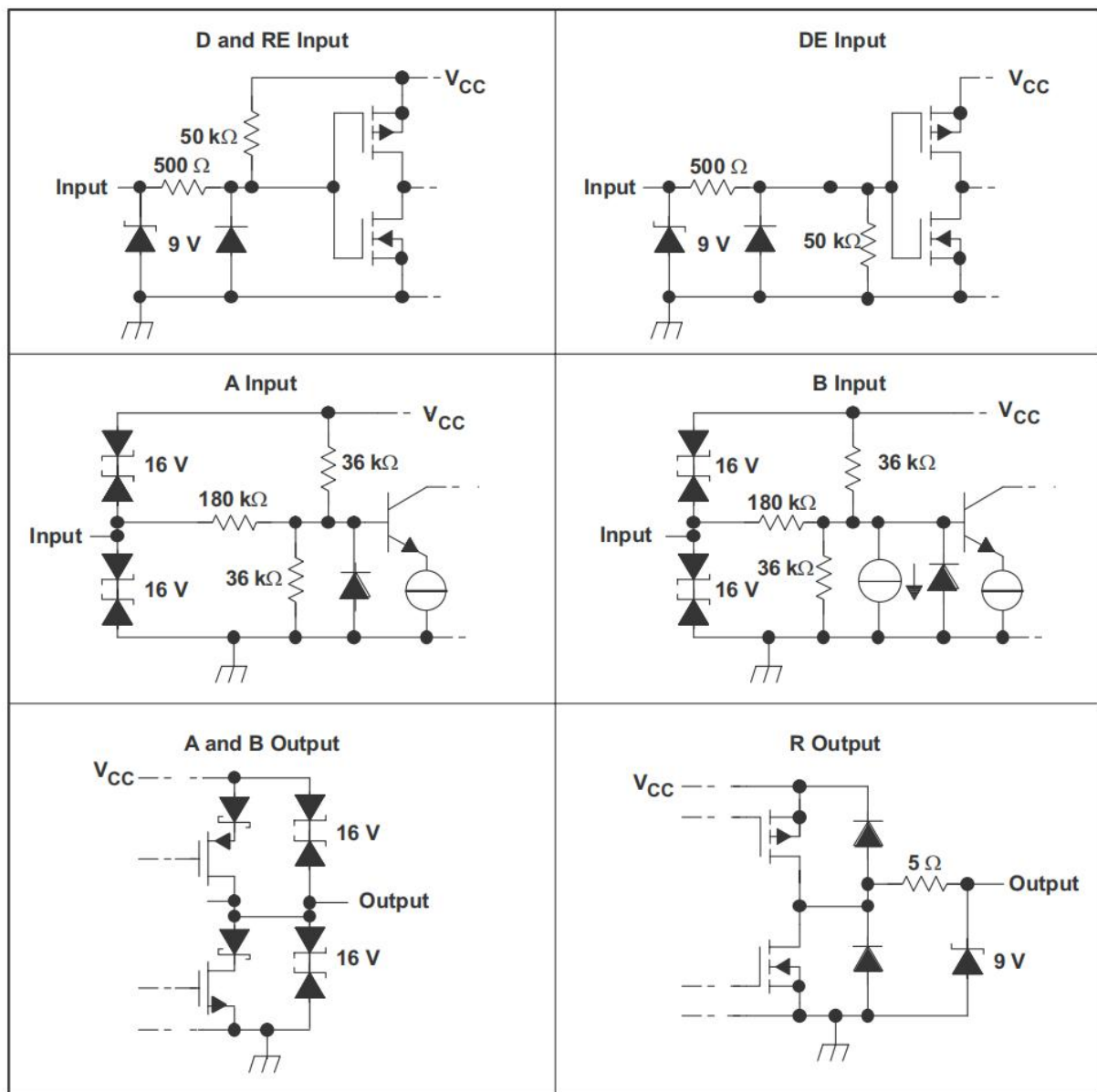


图 7-14. Equivalent Input and Output Schematic Diagrams

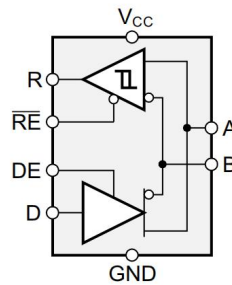


8 Detailed Description

8.1 Overview

The SNx5HVD308xE family of half-duplex RS-485 transceivers is suitable for data transmission at rates up to 200 kbps (for SN65HVD3082E and SN75HVD3082E), 1 Mbps (for SN65HVD3085E), or 20 Mbps (for SN65HVD3088E) over controlled-impedance transmission media (such as twisted-pair cabling). Up to 256 units of SNx5HVD308xE may share a common RS-485 bus due to the family's low bus input currents. The devices also feature a high degree of ESD protection and typical standby current consumption of 1 nA.

8.2 Functional Block Diagram



8.3 Feature Description

The SNx5HVD308xE provides internal biasing of the receiver input thresholds for open-circuit, bus-idle, or short-circuit fail-safe conditions. It features a typical hysteresis of 30 mV in order to improve noise immunity. Internal ESD protection circuits protect the transceiver bus terminals against ± 15 -kV Human Body Model (HBM) electrostatic discharges.

The devices protect themselves against damage due to overtemperature conditions, through the use of a thermal shutdown feature. Thermal shutdown is entered at 165°C (nominal) and causes the device to enter a low-power state with high-impedance outputs.

8.4 Device Functional Modes

When the driver enable pin, DE, is logic high, the differential outputs A and B follow the logic states at data input D. A logic high at D causes A to turn high and B to turn low. In this case the differential output voltage defined as $V_{OD} = V_A - V_B$ is positive. When D is low, the output states reverse, B turns high, A becomes low, and V_{OD} is negative.

When DE is low, both outputs turn high-impedance. In this condition the logic state at D is irrelevant. The DE pin has an internal pull-down resistor to ground, thus when left open the driver is disabled (high-impedance) by default. The D pin has an internal pull-up resistor to V_{CC} , thus, when left open while the driver is enabled, output A turns high and B turns low.

表 8-1. Driver Function Table

INPUT	ENABLE ⁽¹⁾	OUTPUTS ⁽¹⁾		FUNCTION
D	DE	A	B	
H	H	H	L	Actively drive bus High
L	H	L	H	Actively drive bus Low
X	L	Z	Z	Driver disabled
X	OPEN	Z	Z	Driver disabled by default
OPEN	H	H	L	Actively drive bus High by default

(1) H = high level, L = low level, Z = high impedance, X = irrelevant

When the receiver enable pin, $\overline{RE}$, is logic low, the receiver is enabled. When the differential input voltage defined as $V_{ID} = V_A - V_B$ is positive and higher than the positive input threshold, V_{IT+} , the receiver output, R, turns high. When V_{ID} is negative and lower than the negative input threshold, V_{IT-} , the receiver output, R, turns low. If V_{ID} is between V_{IT+} and V_{IT-} the output is indeterminate.



When $\overline{RE}$ is logic high or left open, the receiver output is high-impedance and the magnitude and polarity of V_{ID} are irrelevant. Internal biasing of the receiver inputs causes the output to go failsafe-high when the transceiver is disconnected from the bus (open-circuit), the bus lines are shorted (short-circuit), or the bus is not actively driven (idle bus).

表 8-2. Receiver Function Table

DIFFERENTIAL INPUT	ENABLE ⁽¹⁾	OUTPUT ⁽¹⁾	FUNCTION
$V_{ID} = V_A - V_B$	$\overline{RE}$	R	
$V_{IT+} < V_{ID}$	L	H	Receive valid bus High
$V_{IT-} < V_{ID} < V_{IT+}$	L	?	Indeterminate bus state
$V_{ID} < V_{IT-}$	L	L	Receive valid bus Low
X	H	Z	Receiver disabled
X	OPEN	Z	Receiver disabled by default
Open-circuit bus	L	H	Fail-safe high output
Short-circuit bus	L	H	Fail-safe high output
Idle (terminated) bus	L	H	Fail-safe high output

(1) H = high level, L = low level, Z = high impedance, X = irrelevant, ? = indeterminate

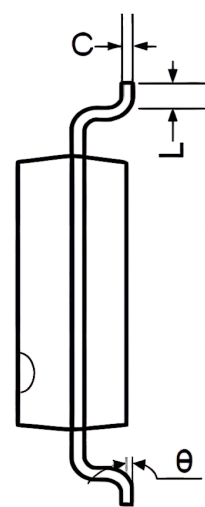
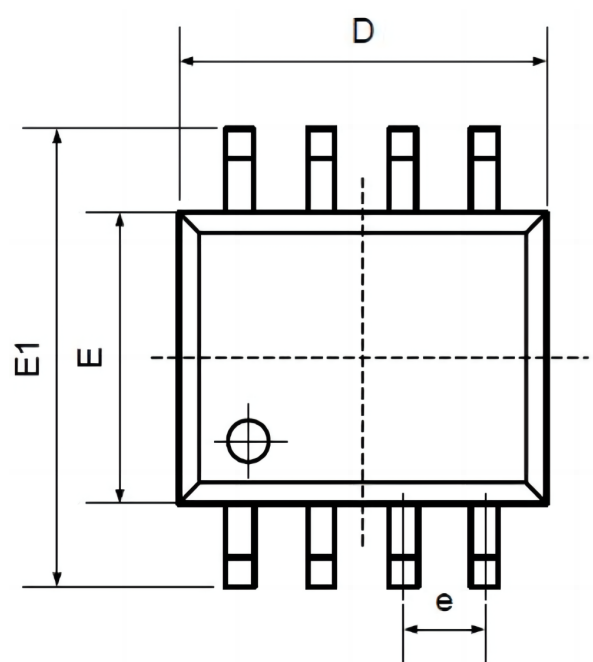


Order information

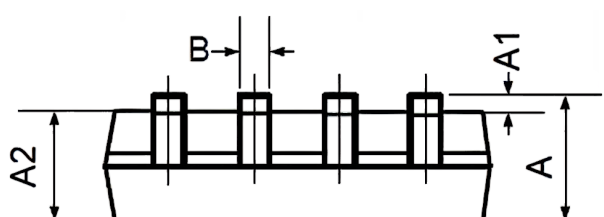
Order Number	Package	Package Quantity	Marking On The park
SN65HVD3082EDGKR-TUDI	MSOP8	Tape,Reel,2500	SN65HVD3082EDGKR
SN65HVD3082EDR-TUDI	SOP8	Tape,Reel,2500	SN65HVD3082EDR
SN65HVD3085EDR-TUDI	SOP8	Tape,Reel,2500	SN65HVD3085EDR
SN65HVD3088EDR-TUDI	SOP8	Tape,Reel,2500	SN65HVD3088EDR



Package SOP8

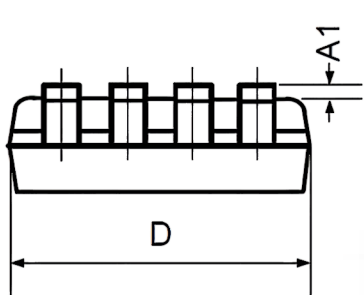
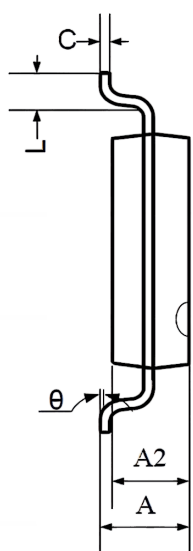
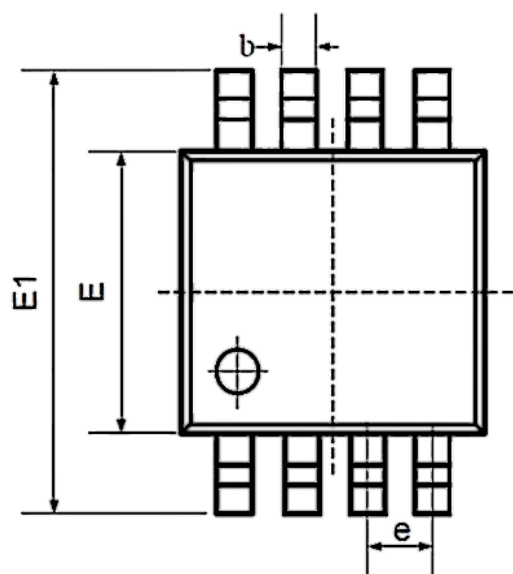


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
B	0.330	0.510	0.013	0.020
C	0.190	0.250	0.007	0.010
D	4.780	5.000	0.188	0.197
E	3.800	4.000	0.150	0.157
E1	5.800	6.300	0.228	0.248
e	1.270TYP		0.050TYP	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°





Package MSOP8



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	0.800	1.200	0.031	0.047
A1	0.000	0.200	0.000	0.008
A2	0.760	0.970	0.030	0.038
b	0.30 TYP		0.012 TYP	
C	0.15 TYP		0.006 TYP	
D	2.900	3.100	0.114	0.122
e	0.65 TYP		0.026 TYP	
E	2.900	3.100	0.114	0.122
E1	4.700	5.100	0.185	0.201
L	0.410	0.650	0.016	0.026
θ	0°	6°	0°	6°



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